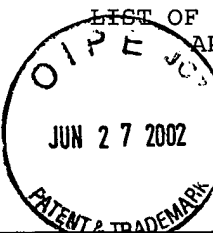


FORM PTO-1449		Atty. Docket No.: R11.12-0763	Appl. No.: 10/046,647
 <p>LIST OF PATENTS AND PUBLICATIONS FOR APPLICANT'S INFORMATION DISCLOSURE STATEMENT</p>		First Named Inventor:	
		Eric R. Lovegren et al.	
		Filing Date	Group Art:
		October 29, 2001	2857

## U.S. PATENT DOCUMENTS

Examiner Initial	Document No.	Date	Name	Class	Sub Class	Filing Date If Appropriate
XS	AA	3,665,466	5/1972	Hibbard	343	12 R
	AB	3,812,422	5/1974	DeCarolus	324	58.5
	AC	3,829,900	9/1974	Ross	73	290 R
	AD	3,853,005	12/1974	Schendel	73	290 R
	AE	3,995,212	11/1976	Ross	324	58.5 B
	AF	4,161,731	7/1979	Barr	343	14
	AG	4,489,601	12/1984	Rao et al.	73	290 R
	AH	4,786,587	11/1988	Kuwabara	430	566
	AI	4,838,690	6/1989	Buckland et al.	356	73.1
	AJ	4,489,601	12/1984	Rao et al.	73	290 R
	AK	5,1157,337	10/1992	Neel et al.	324	632

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	Document No.	Date	Country	Class	Sub Class	Translation Yes No
XS	AL	EP 0 882 957 A2	9.12.98	EPO		X
XS	AM	EP 0 882 956 A2	6.6.97	EPO		X
	AN					

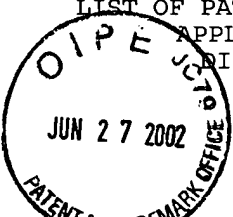
## OTHER ART (Including Author, Title, Date, Pertinent Pages, Etc.)

XS	AO	"Micropower Impulse Radar Technology and Applications" by J. Mast et al., Lawrence Livermore National Laboratory, UCRL-ID-130474, April 15, 1998
XS	AP	"Reflex-Radar Gauging and level measurement for liquids, interface and granular materials", KROHNE Technical Data, December 1996
XS	AQ	"Radar Level Technology Offers Accurate, Noncontact Measurements" by F. Fitch, I&CS, January 1996, pp. 27-30

EXAMINER: 

DATE CONSIDERED: 06/03/03

EXAMINER: Initial if citation considered, whether or not citation is in conformance with MPEP 609; draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

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XS	BA	5,313,168	5/1994	Ogawa	324	663
	BB	5,327,139	7/1994	Johnson	342	22
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	BD	5,500,649	3/1996	Mowrey et al.	342	22
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	BF	5,609,059	3/1997	McEwan	73	290 R
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XS	BK	5,726,578	3/1998	Hook	324	643

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	Document No.	Date	Country	Class	Sub Class	Translation Yes No
	BL					

## OTHER ART (Including Author, Title, Date, Pertinent Pages, Etc.)

XS	BM	"Novel Methods of Measuring Impurity Levels in Liquid Tanks" by Matthias Weib, XP-000767081, IEEE MTT-S Digest, pp. 1651-1654, 08.06.1997
XS	BN	"Determination of Volumetric Water Content in Lossy Geophysical Media Using Time Domain Reflectometry" by B. Oswald et al., Laboratory for Electromagnetic Fields and Microwave Electronics, Swiss Federal Institute of Technology, pp. 2054-2057, 1997
	BO	


EXAMINER:

*Amir S.*

DATE CONSIDERED:

*06/03/03*

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XS	CA	5,811,677	9/1998	Cournance	73	304 R
↓	CB	5,835,053	11/1998	Davis	342	22
↓	CC	5,898,308	4/1999	Champion	324	643
↓	CD	6,198,424	3/2001	Diede et al.	342	22
	CE					
	CF					
	CG					
	CH					
	CI					

## FOREIGN PATENT DOCUMENTS

	Document No.	Date	Country	Class	Sub Class	Translation Yes No
	CJ					
	CK					
	CL					

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XS	CM	"Measurement of Dielectric Properties of Materials by Using Time Domain Reflectometry" by R. Nozaki et al., CH2735-9/90/000-0263, 1999, pp. 263-269
XS	CN	"Continuous Measurement of Cerebral Water Content by Time Domain Reflectometry" by G.G. Kramer et al., IEEE Engineering in Medicine and Biology Societ, Vol. 14, No. 4, 1991, pp. 1593-1594.
	CO	

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*Wing S*

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